

LISTING OF CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

1. (Currently Amended) A semiconductor device comprising:

a semiconductor member having thereon a plurality of electrode terminals; and

a mounting member having a plurality of interconnect pads electrically and mechanically connected to the respective electrode terminals for mounting the semiconductor member on the mounting member,

the interconnect pads forming a plurality of I/O cells including signal terminals, a portion of the I/O cells forming a first group of I/O cells and another portion of the I/O cells forming a second group of I/O cells disposed on an inner position of the mounting member with respect to the first group of I/O cells, the first group of I/O cells including a first row, a second row, a third row, a first column, a second column, and a third column, of interconnect pads disposed to encircle a center of the mounting member, and the second group of I/O cells including a fourth row, a fifth row, a sixth row, a fourth column, a fifth column, and a sixth column of interconnect pads disposed to encircle a center of the mounting member, the first and second groups of I/O cells being disposed directly under the semiconductor member, wherein:

the first group of I/O cells are arranged in ~~the~~ first row, ~~the~~ first column perpendicular to the first row, ~~the~~ second row disposed on an inner position relative to the first row, and ~~the~~ second column that is perpendicular to the second row and disposed on an inner position relative to the first column,

the second group of I/O cells are arranged in ~~the~~ the fourth row, ~~the~~ the fourth column perpendicular to the fourth row, ~~the~~ the fifth row disposed on an inner position relative to the fourth row, and ~~the~~ the fifth column that is perpendicular to the fifth row and disposed on an inner position relative to the fourth column,

each of the first and second rows and first and second columns of the first group of I/O cells is arranged parallel to at least a portion of an outer periphery of the semiconductor member, and each of the third and fourth rows of the second group of I/O cells is arranged parallel to at least a portion of the outer periphery of the semiconductor member, wherein

the first row, the second row, and the third row of the first group of I/O cells are parallel to one side of the semiconductor member,

the first column, the second column, and the third column of the first group of I/O cells are parallel to an another side of the semiconductor member,

the fourth row, the fifth row, and the sixth row of the second group of I/O cells are parallel to the one side of the semiconductor member, and

the fourth column, the fifth column, and the sixth column of the second group of I/O cells are parallel to the another side of the semiconductor member,

the first column and the first row are each arranged parallel to a side of the mounting member so as to surround a center of the mounting member,

the second column and the second row are each arranged parallel to the side of the mounting member so as to surround the center of the mounting member,

the third column and the third row are each arranged parallel to the side of the mounting member so as to surround the center of the mounting member,

the fourth column and the fourth row are each arranged parallel to the side of the

mounting member so as to surround the center of the mounting member,

the fifth column and the fifth row are each arranged parallel to the side of the mounting member so as to surround the center of the mounting member, and

the sixth column and sixth row are each arranged parallel to the side of the mounting member so as to surround the center of the mounting member.

2. (Original) The semiconductor device as defined in claim 1, wherein the semiconductor member is a semiconductor chip, the electrode terminals are internal electrodes disposed on a bottom surface of the semiconductor chip, and the mounting member is a package substrate used for packaging thereon the semiconductor chip.
3. (Previously Presented) The semiconductor device as defined in claim 1, wherein the mounting member is a semiconductor package for mounting the semiconductor member on a mounting substrate, the semiconductor package includes ball electrodes disposed on a bottom surface of a packaging substrate, and the mounting substrate forms a specified circuit by mounting the semiconductor package thereon.
4. (Previously Presented) The semiconductor device as defined in claim 1, wherein the I/O cells include only the signals terminals or terminals for signals, power and ground intermingled among one another.
5. (Previously Presented) The semiconductor device as defined in claim 4, wherein the I/O cells include peripherals.

6. (Previously Presented) The semiconductor device as defined in claim 1, wherein an interconnect line is electrically connected to each of the interconnect pads, and the interconnect lines electrically connected to the interconnect pads of at least one of the I/O cells are formed in a single interconnect layer.

7. (Previously Presented) The semiconductor device as defined in claim 6, wherein the interconnect pads and the interconnect lines electrically connected to the interconnect pads in the single interconnect layer are formed on the surface of a packaging substrate.

8. (Previously Presented) The semiconductor device as defined in claim 7, wherein the interconnect lines connected to the I/O cells located on inner positions extend between the I/O cells located on an outer periphery.

9. (Original) The semiconductor device as defined in claim 6, wherein the interconnect pads and the interconnect lines electrically connected to the interconnect pads are formed as a multi-layered interconnect layer in the substrate.

10. (Original) The semiconductor device as defined in claim 9, wherein at least one of the first group and the second group includes an outer group and an inner group disposed on the inner position of the mounting member with respect to the outer group.

11. (Previously Presented) The semiconductor device as defined in claim 10, wherein the interconnect lines electrically connected to the interconnect pads corresponding to the first group of I/O cells and the interconnect lines electrically connected to the interconnect pads corresponding to the second group of I/O cells are formed in different interconnect layers.